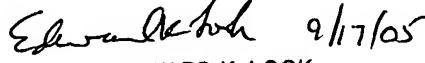


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/644,025		CHANG, SHUN-CHEN	
Examiner				Art Unit			
Dwayne J. White				3745			

ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
415	121.2	415	191	199.5	208.2	211.2	
INTERNATIONAL CLASSIFICATION							
F	0	4	D	29/70			
				/			
				/			
				/			
				/			
 Dwayne J. White (9/16/05) (Assistant Examiner) (Date)				 EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)			
				Total Claims Allowed: 21 O.G. Print Claim(s) 1 O.G. Print Fig. 4A			

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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